查询SN54LS10供应商

捷多邦,专业PCB扩**3415410;4816418;10**, SN54S10, SN7410, SN74LS10, SN74S10 TRIPLE 3-INPUT POSITIVE-NAND GATES SDLS035 - DECEMBER 1983 - REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

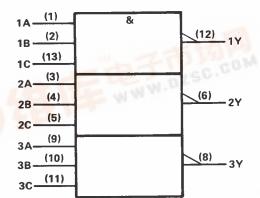
These devices contain three independent 3-input NAND gates.

The SN5410, SN54LS10, and SN54S10 are characterized for operation over the full military temperature range of -55°C to 125°C. The SN7410, SN74LS10, and SN74S10 are characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each gate)

	OUTPUT	NPUTS		INP			
- 5	Y	С	в	A			
	WEDZS	н	н	н			
	н	X	x	L			
	н	X	L	x			
	Н	L	х	x			

logic symbol[†]



[†]This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers shown are for D, J, and N packages.

positive logic

 $Y = \overline{A \cdot B \cdot C} \text{ or } Y = \overline{A} + \overline{B} + \overline{C}$

WWW.DZS

SN5410 ... J PACKAGE SN54LS10, SN54S10 ... J OR W PACKAGE SN7410 ... N PACKAGE SN74LS10, SN74S10 ... D OR N PACKAGE

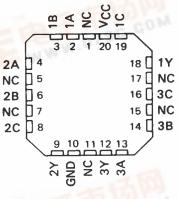
TOP V	IEVV)	
1 U	14	Vcc
2	13	1C
3	12	1Y
4	11	3C
5	10	3B
6	9	3A
7	8	3Y
	1 U 2 3 4 5	3 12 4 11 5 10

SN5410 ... W PACKAGE (TOP VIEW) 1A 1 141 1C 18 2 12 22

1B 🗌	2	13] 3Y
1Y C	3	12] 3C
vcc 🛛	4	11	
2Y 🗌	5	10] зв
2A 🗍	6	9] 3A
2B 🗍	7	8] 2C

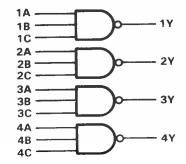
SN54LS10, SN54S10 . . . FK PACKAGE

(TOP VIEW)



NC - No internal connection

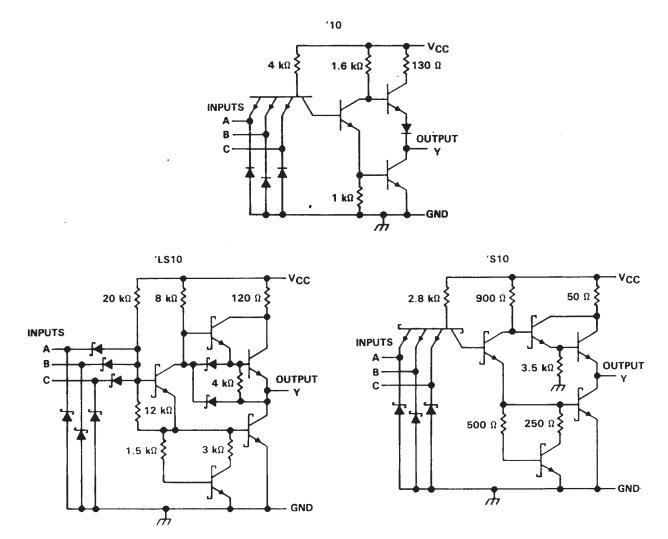
logic diagram (positive logic)





SN5410, SN54LS10, SN54S10, SN7410, SN74LS10, SN74S10 TRIPLE 3-INPUT POSITIVE-NAND GATES SDLS035 – DECEMBER 1983 – REVISED MARCH 1988

schematics (each gate)



Resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

′LS10		7 V
Operating free-air temperature range:	: SN54' 55°C to 1	25°C
	SN74'	70°C
Storage temperature range		50°C

NOTE 1: Voltage values are with respect to network ground terminal.



SN5410, SN7410, TRIPLE 3-INPUT POSITIVE-NAND GATES

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recommended operating conditions

		SN5410)	SN7410			
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	v
VIH High-level input voltage	2			2			v
VIL Low-level input voltage			0.8			0.8	v
IOH High-level output current			- 0.4			- 0.4	mA
IOL Low-level output current			16			16	mA
T _A Operating free-air temperature	- 55		125	0		70	°c

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS T			SN5410			SN741	0	UNIT	
				MIN	TYP‡	MAX	MIN	TYP‡	MAX	
VIK	V _{CC} = MIN, I	≈ — 12 mA				- 1.5			- 1.5	V
V _{OH}	V _{CC} = MIN, V ₁	IL ≖ 0.8 V,	I _{OH} = - 0.4 mA	2.4	3.4		2.4	3.4		v
VOL	V _{CC} = MIN, V _I	IH = 2 V,	I _{OL} = 16 mA		0.2	0.4		0.2	0.4	v
l į	V _{CC} = MAX, V _I	= 5.5 V				1			1	mA
Чн	V _{CC} = MAX, V _I	= 2.4 V				40			40	μA
1 _{1L}	V _{CC} = MAX, V	= 0.4 V				- 1.6			- 1.6	mA
IOS§	V _{CC} = MAX			- 20		- 55	- 18		- 55	mA
Іссн	V _{CC} = MAX, V ₁	= 0 V			3	6		3	6	mA
ICCL	V _{CC} = MAX, V ₁	= 4.5 V			9	16.5		9	16.5	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at $V_{CC} = 5 V$, $T_A = 25^{\circ}C$.

§ Not more than one output should be shorted at a time.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 2)

DADAMETER	FROM	то						
PARAMETER (INPUT) (OUTPUT) TEST CONDITIONS		IS	MIN	ТҮР	MAX	UNIT		
^t PLH	A, B or C	Y	P. = 100 0	- 15 - 5		11	22	ns
^t PHL		·	$R_{L} = 400 \Omega$, $C_{L} = 15 pF$	С _L = 15 рF		7	15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



SN54LS10, SN74LS10, TRIPLE 3-INPUT POSITIVE-NAND GATES

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recommended operating conditions

		SN54LS10			:	UNIT		
	MIN	i	NOM	MAX	MIN	NOM	MAX	
VCC Supply voltage	4.5		5	5.5	4.75	5	5.25	v
VIH High-level input voltage	2				2			v
VIL Low-level input voltage				0.7			0.8	v
IOH High-level output current				- 0.4		· · ·	- 0.4	mA
IOL Low-level output current				4			8	mA
T _A Operating free-air temperature	- 55			125	0		70	°c

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS T			SN54LS10			SN74LS10			
FARAMETER		TEST CONDITIONS F		MIN	TYP‡	MAX	MIN	TYP‡	MAX	UNIT
VIK	V _{CC} = MIN,	l _l = – 18 mA				- 1.5			- 1.5	V
∨он	V _{CC} = MIN,	VIL = MAX,	I _{OH} = 0.4 mA	2.5	3.4		2.7	3.4		v
Max	V _{CC} = MIN,	V _{1H} = 2 V,	1 _{OL} = 4 mA		0.25	0.4			0.4	
VOL	V _{CC} = MIN,	V _{1H} = 2 V,	IOL = 8 mA		· · .			0.25	0.5	V
i,	V _{CC} = MAX,	V ₁ = 7 V				0.1			0.1	mA
Чн	V _{CC} = MAX,	V ₁ = 2.7 V				20			20	μΑ
ЦL	V _{CC} = MAX,	V1 = 0.4 V				- 0.4			- 0.4	mA
los§	V _{CC} = MAX			- 20		- 100	- 20		- 100	mA
Іссн	V _{CC} = MAX,	V ₁ = 0 V		İ	0.6	1.2		0.6	1.2	mA
ICCL	V _{CC} = MAX,	V ₁ = 4.5 V			1.8	3.3		1.8	3.3	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at $V_{CC} = 5 V$, $T_A = 25^{\circ}C$. § Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

switching characteristics, $V_{CC} = 5 V$, $T_A = 25^{\circ}C$ (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN	түр	MAX	UNIT
tPLH	A, B or C	Y	$R_{L} = 2 k\Omega$,	Ci = 15 pF		9	15	ńs
^t PHL			11 <u>2</u> 2 634,	с[– тэрн		10	15	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



SN54S10, SN74S10, TRIPLE 3-INPUT POSITIVE-NAND GATES

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recommended operating conditions

		SN54S10 SN7			SN74S	N74S10		
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V	
VIH High-level input voltage	2			2			v	
VIL Low-level input voltage			0.8			0.8	v	
IOH High-level output current			- 1			- 1	mA	
IOL Low-level output current			20			20	mA	
T _A Operating free-air temperature	- 55		125	0		70	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST CONDITIONS †	SN54S10	SN74S10	UNIT
PARAMETER	TEST CONDITIONS (MIN TYP‡ MAX	MIN TYP‡ MAX	UNIT
VIK	V _{CC} = MIN, I _I = -18 mA	-1.2	-1.2	v
V _{OH}	$V_{CC} = M!N$, $V_{1L} = 0.8 V$, $I_{OH} = -1 mA$	2.5 3.4	2.7 3.4	V
V _{OL}	$V_{CC} = MIN$, $V_{IH} = 2 V$, $I_{OL} = 20 mA$	0.5	0.5	v
Ц	V _{CC} = MAX, V _I = 5.5 V	1	1	mA
Ιн	V _{CC} = MAX, V _I = 2.7 V	50	50	μA
ΪL	V _{CC} = MAX, V _I = 0.5 V	-2	-2	mA
IOS §	V _{CC} = MAX	-40 -100	-40 -100	mA
^I ССН	V _{CC} = MAX, V _I = 0 V	7.5 12	7.5 12	mA
ICCL	V _{CC} = MAX, V _I = 4.5 V	15 27	15 27	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at $V_{CC} = 5 V$, $T_A = 25^{\circ}C$. § Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

switching characteristics, V_{CC} = 5 V, TA = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS		MIN 1	ТҮР	MAX	UNIT
^t PLH	A, B or C	Y	R _L = 280 Ω,	CL = 15 pF		3	4.5	ns
^t ₽HL						3	5	ns
^t PLH			RL = 280 Ω,	С _L = 50 рF		4.5		ns
^t PHL						5		ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



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